

10 JUN 2006

Docket No.: 12810-00278-US1
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Lars Wittenbecher et al.

Application No.: National Phase of PCT/EP04/014275

Confirmation No.: N/A

Filed: Concurrently Herewith

Art Unit: N/A

For: COPPER(I) FORMATE COMPLEXES

Examiner: Not Yet Assigned

INFORMATION DISCLOSURE STATEMENT (IDS)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Pursuant to 37 CFR 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO/SB/08. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement accompanies the new patent application submitted herewith.

Applicant has not submitted copies of each cited U.S. patent and U.S. patent application as required by 37 CFR 1.98(a)(2)(i), amended October 2004, as the U.S. Patent and Trademark Office has waived this requirement for all U.S. patent applications. Applicant submits herewith copies of foreign and non-patents in accordance with 37 CFR 1.98(a)(2).

In accordance with 37 CFR 1.97(g), the filing of this Information Disclosure Statement shall not be construed to mean that a search has been made or that no other material information

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as defined in 37 CFR 1.56(a) exists. In accordance with 37 CFR 1.97(h), the filing of this Information Disclosure statement shall not be construed to be an admission that any patent, publication or other information referred to therein is "prior art" for this invention unless specifically designated as such.

It is submitted that the Information Disclosure Statement is in compliance with 37 CFR 1.98 and the Examiner is respectfully requested to consider the listed references.

The Director is hereby authorized to charge any deficiency in the fees filed, asserted to be filed or which should have been filed herewith (or with any paper hereafter filed in this application by this firm) to our Deposit Account No. 03-2775, under Order No. 12810-00278-US1.

Dated: June 16, 2006

Respectfully submitted,

By  52834

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PTO/SB/08a/b (07-05)
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Substitute for form 1449A/B/PTO		Complete if Known Application Number Not Yet Assigned Filing Date Concurrently Herewith First Named Inventor Lars Wittenbecher Art Unit N/A Examiner Name Not Yet Assigned Attorney Docket Number 12810-00278-US1	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)			
Sheet	1	of	2

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	AA*	US-5,141,602	08-25-1992	Chen et al.	

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ -Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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	BB	JP-06/184 749	07-05-1994	Dowa Mining Co Ltd	
	BC	WO-01/13426	02-22-2001	Steag RTP Systems Inc.	
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	BG	WO-01/94291	12-13-2001	Chi, Yun	
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	BI	EP-1 077 084	02-21-2001	Mitsubishi Gas Chemical Co Inc	
	BJ	EP-0 368 231	05-16-1990	Mitsubishi Gas Chemical Co Inc	
	BK	JP-11/193 461	07-21-1999	Arisawa MFG Co Ltd	
	BL	WO-036 053895	07-03-2003	El Du Pont De Nemours and Co	

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NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T ²
	CA	T.T. Kodas et al., The Chemistry of Metal CVD, 1994, p. 239-302			
	CB	D.K. Sohn et al., Ahn in Electrochem. Soc. 144 (1977), 3592-3596			
	CC	F.A. Cotton et al., Inorg. Chem. 39 (2000), 6072-6079			
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	CG	K. Kohler et al., Organometallics 22 (2003) 4426-4432			
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Examiner Signature	/Robert Vetere/ (03/25/2010)	Date Considered	
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Application Number	Not Yet Assigned 33-03
		Filing Date	Concurrently Herewith
		First Named Inventor	Lars Wittenbecher
		Art Unit	N/A
		Examiner Name	Not Yet Assigned
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CO	D.A. Edwards, J. Chem. Soc. Dalton Trans. 1973, 2463-2468	
CP	B. Begiun et al., J. Organomet. Chem. 208 (1981) C18-C20	
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CV	Inorg. Chem., vol. 24, n. 6, 1985, 924-931, XP002347078	

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